

Notice of References Cited	Application/Control No. 10/611,896	Applicant(s)/Patent Under Reexamination LEE ET AL.	
	Examiner Thien F Tran	Art Unit 2811	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	B	US-5,416,341	05-1995	Hayama, Hiroshi	257/59
	C	US-			
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	L	US-			
	M	US-			

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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